

Notice of References Cited

Application/Control No.

09/664,329

Applicant(s)/Patent Under
Reexamination
CHAPMAN ET AL.

Examiner

Benny Q. Tieu

Art Unit

2642

Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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